4/17/2012

RELIABILITY MONITOR REPORT
FOR

Dallas 0.6µm Silicon Gate CMOS (E6)

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

DS1851

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 1737 QUANTITY: 77 FAILS: 0 FITS: 65.7

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2011 and 3/31/2012 .

Process Information:

Process Description: Dallas 0.6µm Silicon Gate CMOS (E6)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	0720	DS1851	125C, 5.5 VOLTS	192 HRS	77	0	QK707606BBA
				Total:		**0**	

FAILURE RATE: MTTF (YRS): 1737 QUANTITY: 77 FAILS: 0 FITS: 65.7